
**Surface chemical analysis —
Secondary-ion mass spectrometry —
Determination of relative sensitivity
factors from ion-implanted reference
materials**

*Analyse chimique des surfaces — Spectrométrie de masse des ions
secondaires — Détermination des facteurs de sensibilité relative à
l'aide de matériaux de référence à ions implantés*

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Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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This document was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 6, *Secondary ion mass spectrometry*.

This second edition cancels and replaces the first edition (ISO 18114:2003), which has been technically revised.

The main changes compared to the previous edition are as follows:

- [Formula \(1\)](#) has been corrected;
- in [Clause 5](#), Notes 1 and 2 have been modified.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

Ion-implanted materials are commonly used in secondary-ion mass spectrometry for the calibration of instruments. This document was prepared to provide a uniform method for determining the relative sensitivity factor of an element in a specified matrix from an ion-implanted reference material, and to show how the concentration of the element in a different sample of the same matrix material can be determined.

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